

# **ELECTROSTATIC DISCHARGE (ESD) TESTING REPORT**

Machine Model (MM)

Report No: <K230317030> Log-in Date: 2023/03/17 Report Date: 2023/10/12

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MA-tek is the only analysis service laboratory in Taiwan that has been certified under ISO/IEC 15408 (Common Criteria for Information Technology Security Evaluation). It possesses the qualifications to provide security assessment and testing services for information and communication products ranging from EAL1 to EAL6.

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## 1 Background Information

#### 1.1 Client Information

Applicant/Department: CorePower Technology Co., Ltd.

Product: CP02B

#### 1.2 Testing Inquiry

Test Item: Machine Model (MM) Package/Pin Count: SOT-23-3 Reference: JESD22-A115C

Zap Interval:  $\geq$  0.5 S Zap : 1 pulse

Temperature:25  $\pm$  5 °C Humidity:55  $\pm$  5% RH

Test Instrument: MK2-TE(1) Calibration Date: 2023/03/28

Test Voltage:

(±)50V, (±)100V, (±)200V

#### 1.3 Pass / Fail Criteria

After testing, DUT no longer fulfills requirements of  $\pm$  30% voltage drift at  $\pm$  1uA reference current and compliance within 10% V+I envelope around REFERENCE I-V curve (pre-zap).

## **2** Testing Summary

|                         | Test Voltage | Pin Combination | Sample | Pass Level |  |
|-------------------------|--------------|-----------------|--------|------------|--|
|                         | 50V          | All(±)-PWR      | 3      | ±50V       |  |
| Sensitivity Pass: ±200V | 507          | All(±)-GND      | 3      |            |  |
|                         | 100V         | AII(±)-PWR      | 3      | ±100V      |  |
|                         |              | All(±)-GND      | 3      |            |  |
| Class-B                 | 200V         | AII(±)-PWR      | 3      | ±200V      |  |
| JESD22-A115C            | 200 V        | All(±)-GND      | 3      |            |  |
|                         |              |                 |        |            |  |

Class-A : 0 V to < 200 V Class-B : 200 V to < 400 V

Class-C : ≥ 400 V

NOTE: Red color in raw data indicates failed pins.

<sup>\*</sup> DUT failed at the first level of test condition, defined by client.

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# 3 Testing Items and Raw Data

## 3.1 Pin Assignment

| Pin Group | PAD Pins |
|-----------|----------|
| Ю         | 4        |
| PWR       | 3        |
| GND       | 2        |

#### 3.2 Raw Data

|           | 50V                   |   |            |      |      |            |      |      |  |
|-----------|-----------------------|---|------------|------|------|------------|------|------|--|
| (Unit: V) |                       |   | All(±)-PWR |      |      | AII(±)-GND |      |      |  |
|           | Test Pin Fail Voltage |   |            | #14  | #15  | #13        | #14  | #15  |  |
| 2         | VSS                   | 2 | Pass       | Pass | Pass | N/A        | N/A  | N/A  |  |
| 3         | VDD                   | 3 | N/A        | N/A  | N/A  | Pass       | Pass | Pass |  |
| 4         | VM                    | 4 | Pass       | Pass | Pass | Pass       | Pass | Pass |  |

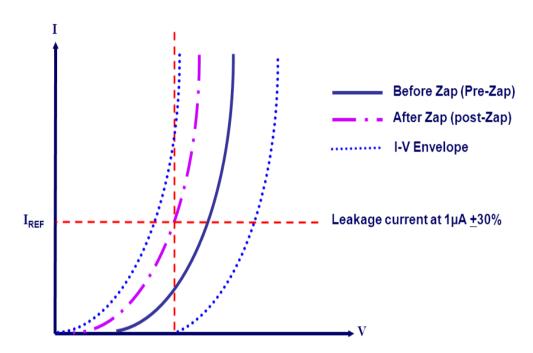
|           | 100V                  |   |            |      |      |            |      |      |  |
|-----------|-----------------------|---|------------|------|------|------------|------|------|--|
| (Unit: V) |                       |   | All(±)-PWR |      |      | All(±)-GND |      |      |  |
|           | Test Pin Fail Voltage |   |            | #17  | #18  | #16        | #17  | #18  |  |
| 2         | VSS                   | 2 | Pass       | Pass | Pass | N/A        | N/A  | N/A  |  |
| 3         | VDD                   | 3 | N/A        | N/A  | N/A  | Pass       | Pass | Pass |  |
| 4         | VM                    | 4 | Pass       | Pass | Pass | Pass       | Pass | Pass |  |

|           | 200V                  |   |            |      |      |            |      |      |  |
|-----------|-----------------------|---|------------|------|------|------------|------|------|--|
| (Unit: V) |                       |   | AII(±)-PWR |      |      | All(±)-GND |      |      |  |
|           | Test Pin Fail Voltage |   |            | #20  | #21  | #19        | #20  | #21  |  |
| 2         | VSS                   | 2 | Pass       | Pass | Pass | N/A        | N/A  | N/A  |  |
| 3         | VDD                   | 3 | N/A        | N/A  | N/A  | Pass       | Pass | Pass |  |
| 4         | VM                    | 4 | Pass       | Pass | Pass | Pass       | Pass | Pass |  |

#### 3.3 Appendix (Pass/Fail Criteria)

Note

After testing, DUT no longer fulfills requirements of  $\pm$  30% voltage drift at  $\pm$  1uA reference current and compliance within 10% V+I envelope around REFERENCE I-V curve (pre-zap).



Pass/Fail Criteria: Variation of Leakage Current and I-V Shift in Pre-Zap and Post-Zap curves

## **MA-tek Milestone, Accreditation & Certificates**

MA-tek is a company with ISO 9001, IECQ 17025 and ISO 27001 certifications and is the only lab in Taiwan awarded the Industrial Excellence Award by the IDB (2008). MA-tek's method of dimension measurement of analytical data can be traced back to the NIST Standard (National Institute of Standard and Technology).

MA-tek is the only analysis service laboratory in Taiwan that has been certified under ISO/IEC 15408 (Common Criteria for Information Technology Security Evaluation). It possesses the qualifications to provide security assessment and testing services for information and communication products ranging from EAL1 to EAL6.

- 2004 Certified by ISO 9001 and IECQ 17025.
- 2006 Elected as the Distinguished Enterprise by the Industry Development Bureau (IDB).
- 2006 Awarded #32 in the Taiwan Top 50 and #157 in the Asia Top 500 Fastest Growing Companies by Deloitte.
- 2008 Awarded the best performance company of Industrial Excellence Award by the Economy Ministry's Industry Development Bureau (IDB).
- 2009 Listed on the Taiwan OTC market (3587)
- 2012 Awarded #474 in the Asia Top 500 Fastest Growing Companies by Deloitte.
- 2013 A+ companies in Taiwan by Global Views Monthly Magazine.
- 2015 Certified by ISO 27001.
- 2017 JS Lab certificated by TUV NORD Certification in Automotives
- 2018 Passed the ANSI/ESD S20.20 certification in ESD protection
- 2020 Certified by ISO/IEC 15408 CC EAL6 in Information Security.

  Ranked #83 among Top 100 rapid growth companies in Taiwan by CommonWealth Magazine
- 2021 MA-tek (Shanghai) certificated by High and New Tech Enterprises Certification.
- 2022 Certificated by CNAS-CL01.











ISO / IEC 27001

ISO / IEC 15408

IECQ 17025

CNAS-CL01

ISO 9001